# Notice of References Cited

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10/087,066	Maier		
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# **U.S. PATENT DOCUMENTS**

		Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Cla	ssification <sup>2</sup>
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### FOREIGN PATENT DOCUMENTS

		Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Clas	sification <sup>2</sup>
	N	WO 0,046,184 •	8/2000	wo	Charles et al.		
	0	WO 92/08714 •	5/1992	wo	Robson		
	Р	JP 59-152303 ▶	8/1984	JP	Katsuda		
•	a	JP 59-157004 🕴	9/1984	JP	Katsuda		
	R						
	s				1100		
	т						

#### **NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Sekiguchi et al., Chem. Abstract 115:256727, 1991.
٧	Ziessel et al., Chem. Abstract 134:193375, 2000.
w	Romero et al., Chem. Abstract 130:296640, 1999.
x	Nakayama et al., Chem. Abstract 129:189329, 1998.

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>&</sup>lt;sup>1</sup> Dates in MM-YYYY format are publication dates.

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# U.S. PATENT DOCUMENTS

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### **NON-PATENT DOCUMENTS**

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		Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
	U	Nitschke et al., Chem. Abstract 128:321535, 1998.
	v	Chamchoumis et al., Chem. Abstract 131:82037, 1999.
	w	Houghton et al., Chem. Abstract 127:256664, 1997.
	x	Ziessel et al., Chem. Abstract 125:221516, 1996.

<sup>2</sup> Classifications may be U.S. or foreign.

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>&</sup>lt;sup>1</sup> Dates in MM-YYYY format are publication dates.

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T					

#### **NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Inouye et al., Chem. Abstract 124:146602, 1995.
v	Koevari et al., Chem. Abstract 123:198925, 1995.
w	Potts et al., Chem. Abstract 118:233840, 1993.
x	Butler et al., Chem. Abstract 115:207819, 1991.

<sup>2</sup> Classifications may be U.S. or foreign.

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

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